

Search Notes



Application/Control No.

10/784,302

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

YAMAMOTO ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	112	06.10.05	Nh
	322	T	T
323	285		
	284		
327	577	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	06.10.05	Nh
See attachment		